THE NATIONAL UNIVERSITY of SINGAPORE
Department of Industrial & Systems Engineering

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IEEE Reliability Society, Singapore Section

JOINT SEMINAR
On

How reliable are the results of reliability test performed in waferfabs?

Speaker: Dr. Luc Tielemans, CHIRON TECHNOLOGY Pte Ltd, Singapore

Date: 7 February, 2003 (Friday)

Time: 3:00 p.m. to 4:30 p.m.

Venue: EA-06-03, Faculty of Engineering, NUS

Abstract: In the waferfabs, reliability tests are performed for 2 reasons: i. to predict lifetime and ii. to monitor the wafer processes for reliability behaviour. In the prediction of life time large prediction levels can be observed on the results. This large uncertainty is due to different types of errors made during the reliability test and data analysis. All types of errors using the "time to failure" test approach will be discussed and methods are proposed to improve how reliability tests can be improved.

Biography: Luc Tielemans received his higher education and worked at Catholic University Leuven (Belgium) and received his PhD in 1986. After serving the Belgium army, he worked for IMEC (Interuniversity Micro-Electronics Center) as scientific researcher and later in Salzgitter Electronic (Flintbek, Germany), as head of department until 1993 before becoming general manager of DESTIN N.V. (Diepenbeek, Belgium), a Spin-Off from IMEC. In 2002, he is located in Singapore as technical director of Chiron Technology Pte Ltd. Dr Tielemans has published many papers in reliability, Solid State Physics and Packaging and Interconnection Technology. He gave tutorials at the International Symposium on Reliability Physics and Failure Analysis in USA in 2001 and 2002. Dr Tielemans also holds a US patent.

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